Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/502,095	SHIBUYA ET AL.	
Examiner	Art Unit	
David Sample	1755	

SEARCHED				
Class	Subclass	Date	Examiner	
502	60	4/2/2007	All	
	64			
	73			
	203,224			
	225,228	٧	V	
	231	4/2/2007	All	
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INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
•	DATE	EXMR		
East searched	4/2/2007	QU/		
PALM Inventor name search	4/2/2007	All		
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